

<b>QUALIFICATION STATUS – LTC7150S</b> <b>0.35 BCD in 42-CSP_BGA 6X5-AEK</b>			
<b>TEST</b>	<b>SPECIFICATION</b>	<b>SAMPLE SIZE</b>	<b>RESULTS</b>
Highly Accelerated Stress Test (HAST)* <sup>1</sup>	JEDEC <i>JESD22-A110</i>	<b>3*77</b>	<b>Pass</b>
Temperature Cycling (TC) * <sup>1</sup>	JEDEC <i>JESD22-A104</i>	<b>3*77</b>	<b>Pass</b>
Unbiased Highly Accelerated Stress Test (UHAST) * <sup>1</sup>	JEDEC <i>JESD22-A102</i>	<b>3*77</b>	<b>Pass</b>
High Temperature Storage Life (HTSL) <sup>1</sup>	JEDEC <i>JESD22-A103</i>	<b>1*45</b>	<b>Pass</b>
High Temperature Operating Life (HTOL) <sup>2</sup>	JEDEC <i>JESD22-A108</i>	<b>3*77</b>	<b>Pass</b>
Early Life Failure Rate Operating Life (ELFR) <sup>1</sup>	JEDEC <i>JESD22-A108</i>	<b>3*800</b>	<b>Pass</b>
Latch-Up <sup>1</sup>	JEDEC <i>JESD78</i>	<b>&gt; ±100mA</b>	<b>Pass</b>
Electrostatic Discharge <i>Human Body Model</i> <sup>1</sup>	ESDA/JEDEC <i>JS-001</i>	<b>3/voltage</b>	<b>Pass 2000V</b>
Electrostatic Discharge <i>Field-Induced Charged Device Model</i> <sup>1</sup>	JEDEC <i>JESD22-C101</i>	<b>3/voltage</b>	<b>Pass 4000V</b>

\*Preconditioned per JEDEC/IPC J-STD-020

<sup>1</sup> Pre and post stress electrical test was performed at room and hot temperatures.

<sup>2</sup> Pre and post stress electrical test was performed at room, hot and cold temperature